AMENDMENTS TO THE SPECIFICATION

Please replace Paragraphs [0052]-[0054] with the following paragraph rewritten in amendment format:

[0052] Using the optical disc thickness measuring apparatus as described above, raw data for determining the thickness of the optical disc such as an HD-DVD may be ~~measured by detecting an~~obtained. Detected variations, according to changes in wave length, of the intensity of a reflective light ~~according to the wavelength of the light~~are treated as a first spectrum of data ~~for each wavelength~~ (Step S10). An example of ~~The detected~~ first spectrum data is~~are~~ illustrated in FIG. 5A.

[0053] The ~~detected~~ first spectrum data ~~for each wavelength~~ is then converted ~~into spectrum data for each wavelength~~ into a second spectrum of values~~value~~ that is a function not only of a wavelength ~~reflective~~ but also of the refractive index (Step S20).

[0054] An equation for ~~processing the~~converting the first spectrum into the second spectrum may be expressed by the following Equation 3.

Please replace Paragraph [0067] with the following paragraph rewritten in amendment format:

[0067] By using the function relationship with respect to $\Delta(n(\lambda)/\lambda)$ of the intensity of the light obtained according to the equation as described above, the apparatus can obtain the second spectrum which is a function of ~~data where~~ the refractive index ~~is reflected into the~~ and separately also is a function of wavelength. In this regard, FIG. 5B illustrates an example of a graph ~~setting~~ that plots the intensity of reflective light as a vertical axis and a value $n(\lambda)/2\lambda$ ~~in which a refractive index is reflected by a function of a wavelength~~ as a horizontal axis. In other words, in the plot of Fig. 5B, intensity varies according to a first factor that is the index of refraction n and a separate second factor that is λ. It is noted that the index of refraction is a function of λ, namely n(λ).